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Understanding Embedded - CPLDs (Complex Programmable Logic Devices)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

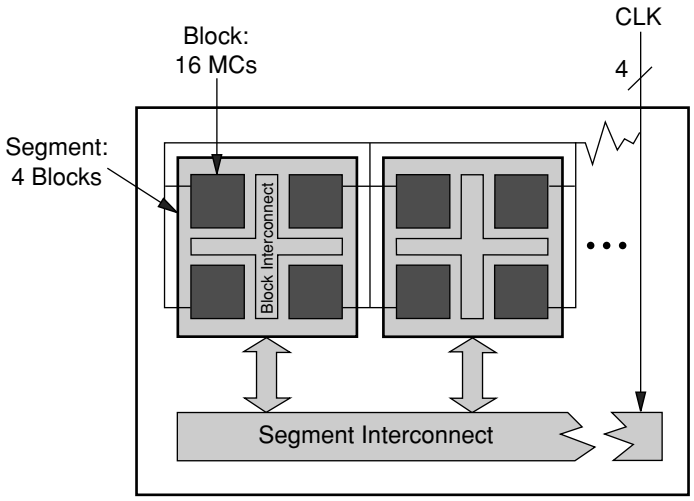
Applications of Embedded - CPLDs

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	7.5 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	-
Number of Macrocells	384
Number of Gates	-
Number of I/O	120
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	160-BQFP
Supplier Device Package	160-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/m5lv-384-120-7yi

and both the 3.3-V and the 5-V device versions are in-system programmable through an IEEE 1149.1 Test Access Port (TAP) interface.

FUNCTIONAL DESCRIPTION

The MACH 5 architecture consists of PAL blocks connected by two levels of interconnect. The **block interconnect** provides routing among 4 PAL blocks. This grouping of PAL blocks joined by the block interconnect is called a **segment**. The second level of interconnect, the **segment interconnect**, ties all of the segments together. The only logic difference between any two MACH 5 devices is the number of segments. Therefore, once a designer is familiar with one device, consistent performance can be expected across the entire family. All devices have four clock pins available which can also be used as logic inputs.



20446G-001

Figure 1. MACH 5 Block Diagram

The MACH 5 PAL blocks consist of the elements listed below (Figure 2). While each PAL block resembles an independent PAL device, it has superior control and logic generation capabilities.

- I/O cells
- Product-term array and Logic Allocator
- Macrocells
- Register control generator
- Output enable generator

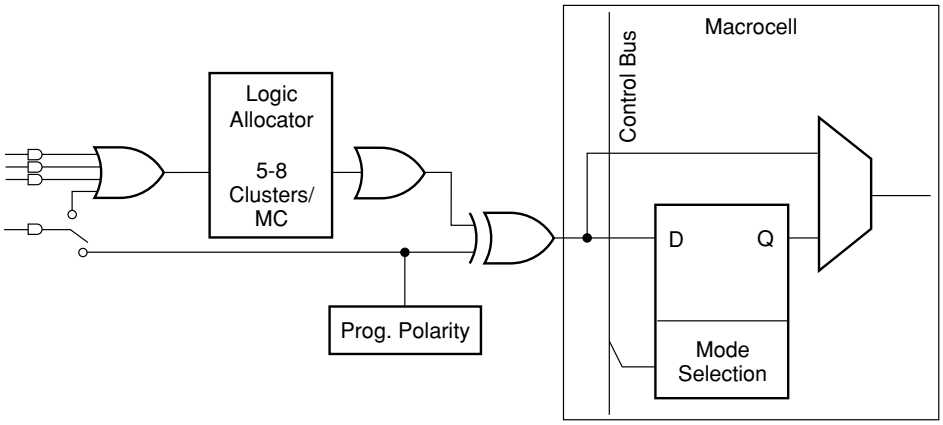
I/O Cells

The I/Os associated with each PAL block have a path directly back to that PAL block called **local feedback**. If the I/O is used in another PAL block, the **interconnect feeder** assigns a **block interconnect** line to that signal. The interconnect feeder acts as an input switch matrix. The block and segment interconnects provide connections between any two signals in a device. The **block feeder** assigns block interconnect lines and local feedback lines to the PAL block inputs.

Macrocells

The macrocells for MACH 5 devices consist of a storage element which can be configured for combinatorial, registered or latched operation (Figure 3). The D-type flip-flops can be configured as T-type, J-K, or S-R operation through the use of the XOR gate associated with each macrocell.

Each PAL block has the capability to provide two input registers by using macrocells 0 and 15. In order to use this option, these macrocells must be accessed via the I/O pins associated with macrocells 3 and 12, respectively. Once the macrocell is used as an input register, it cannot be used for logic, so its clusters can be re-directed through the logic allocator to another macrocell. The
I/O pins associated with macrocells 0 and 15 can still be used as input pins. Although the I/O pins for macrocells 3 and 12 are used to connect to the input registers, these macrocells can still be used as "buried" macrocells to drive device logic via the matrix.



20446G-003

Figure 3. Macrocell Diagram

Control Generator

The control generator provides four configurable clock lines and three configurable set/reset lines to each macrocell in a PAL block. Any of the four clock lines and any of the three set/reset lines can be independently selected by any flip-flop within a block. The clock lines can be configured to provide synchronous global (pin) clocks and asynchronous product term clocks, sum term clocks, and latch enables (Figure 4). Three of the four global clocks, as well as two product-term clocks and one sum-term clock, are available per PAL block. Positive or negative edge clocking is available as well as advanced clocking features such as **complementary** and **biphase** clocking. Complementary clocking provides two clock lines exactly 180 degrees out of phase, and is useful in applications such as fast data paths. A biphase clock line clocks flip-flops on both the positive and negative edges of the clock. The configuration options for the four clock lines per PAL block are as follows:

Clock Line 0 Options

- Global clock (0, 1, 2, or 3) with positive or negative edge clock enable
- Product-term clock (A*B*C)
- Sum-term clock (A+B+C)

Clock Line 1 Options

- Global clock (0, 1, 2, or 3) with positive edge clock enable
- Global clock (0, 1, 2, or 3) with negative edge clock enable

MULTIPLE I/O AND DENSITY OPTIONS

The MACH 5 family offers six macrocell densities in a number of I/O options. This allows designers to choose a device close to their logic density and I/O requirements, thus minimizing costs. For the same package type, every density has the same pin-out. With proper design considerations, a design can be moved to a higher or lower density part as required.

IEEE 1149.1 - COMPLIANT BOUNDARY SCAN TESTABILITY

Most MACH 5 devices have boundary scan registers and are compliant to the IEEE 1149.1 standard. This allows functional testing of the circuit board on which the device is mounted through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test node data to be captured and shifted out for verification. In addition, these devices can be linked into a board-level serial scan path for more complete board-level testing.

IEEE 1149.1 - COMPLIANT IN-SYSTEM PROGRAMMING

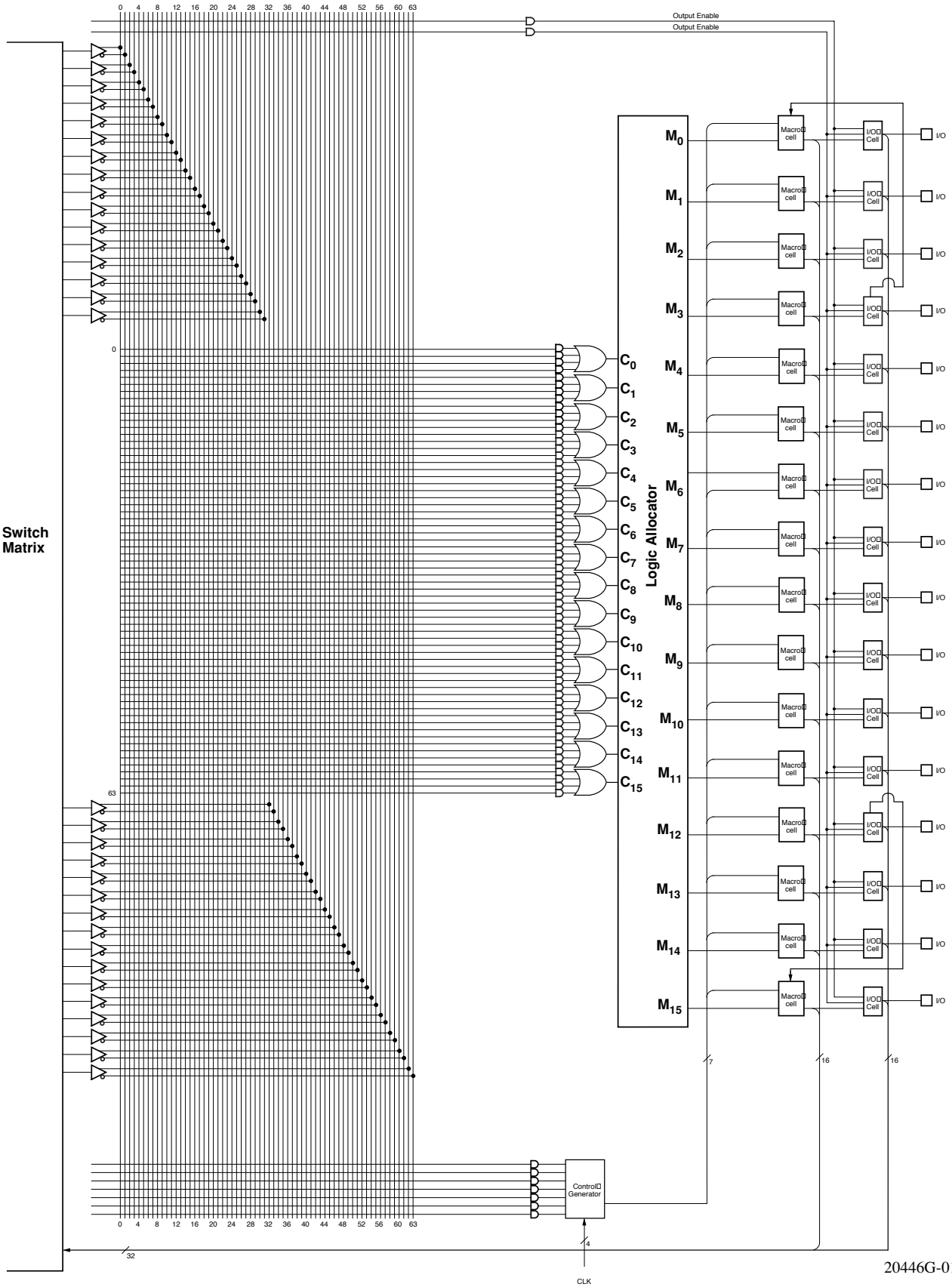
Programming devices in-system provides a number of significant benefits including: rapid prototyping, lower inventory levels, higher quality, and the ability to make in-field modifications. All MACH 5 devices provide in-system programming (ISP) capability through their IEEE 1149.1-compliant Boundary Scan Test Access Port. By using the IEEE 1149.1-compliant Boundary Scan Test Access Port as the communication interface through which ISP is achieved, customers get the benefit of a standard, well-defined interface.

MACH 5 devices can be programmed across the commercial temperature and voltage range. The PC-based LatticePRO software facilitates in-system programming of MACH 5 devices. LatticePRO software takes the JEDEC file output produced by design implementation software, along with information about the Boundary Scan chain, and creates a set of vectors that are used to drive the Boundary Scan chain. LatticePRO software can use these vectors to drive a Boundary Scan chain via the parallel port of a PC. Alternatively, LatticePRO software can output files in formats understood by common automated test equipment. This equipment can then be used to program MACH 5 devices during the testing of a circuit board.

PCI COMPLIANT

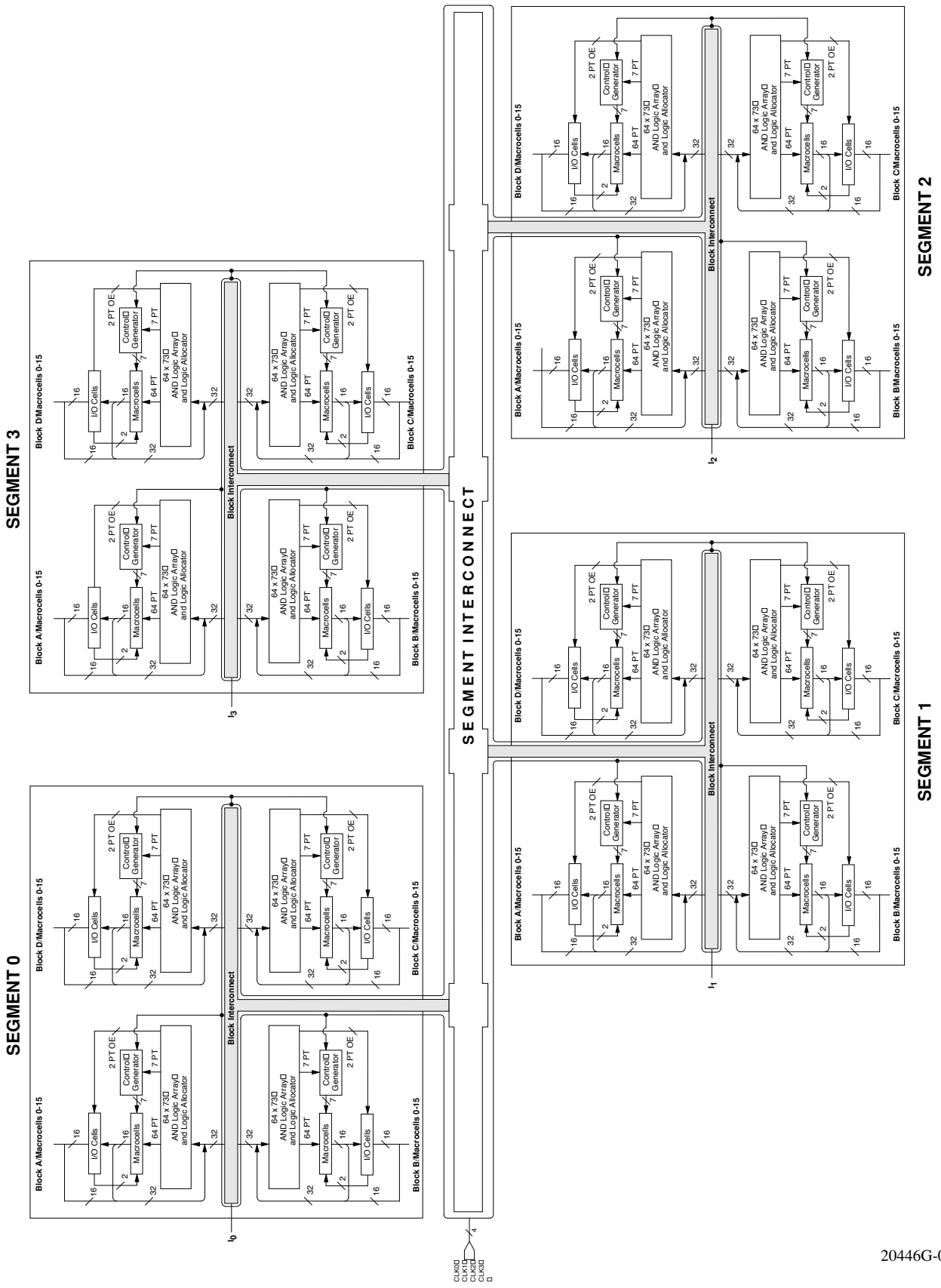
MACH 5 devices in the -5/-6/-7/-10/-12 speed grades are compliant with the *PCI Local Bus Specification* version 2.1, published by the PCI Special Interest Group (SIG). The 5-V devices are fully PCI-compliant. The 3.3-V devices are mostly compliant but do not meet the PCI condition to clamp the inputs as they rise above V_{CC} because of their 5-V input tolerant feature. MACH 5 devices provide the speed, drive, density, output enables and I/Os for the most complex PCI designs.

MACH 5 PAL BLOCK



Select devices have been discontinued.
See Ordering Information section for product status.

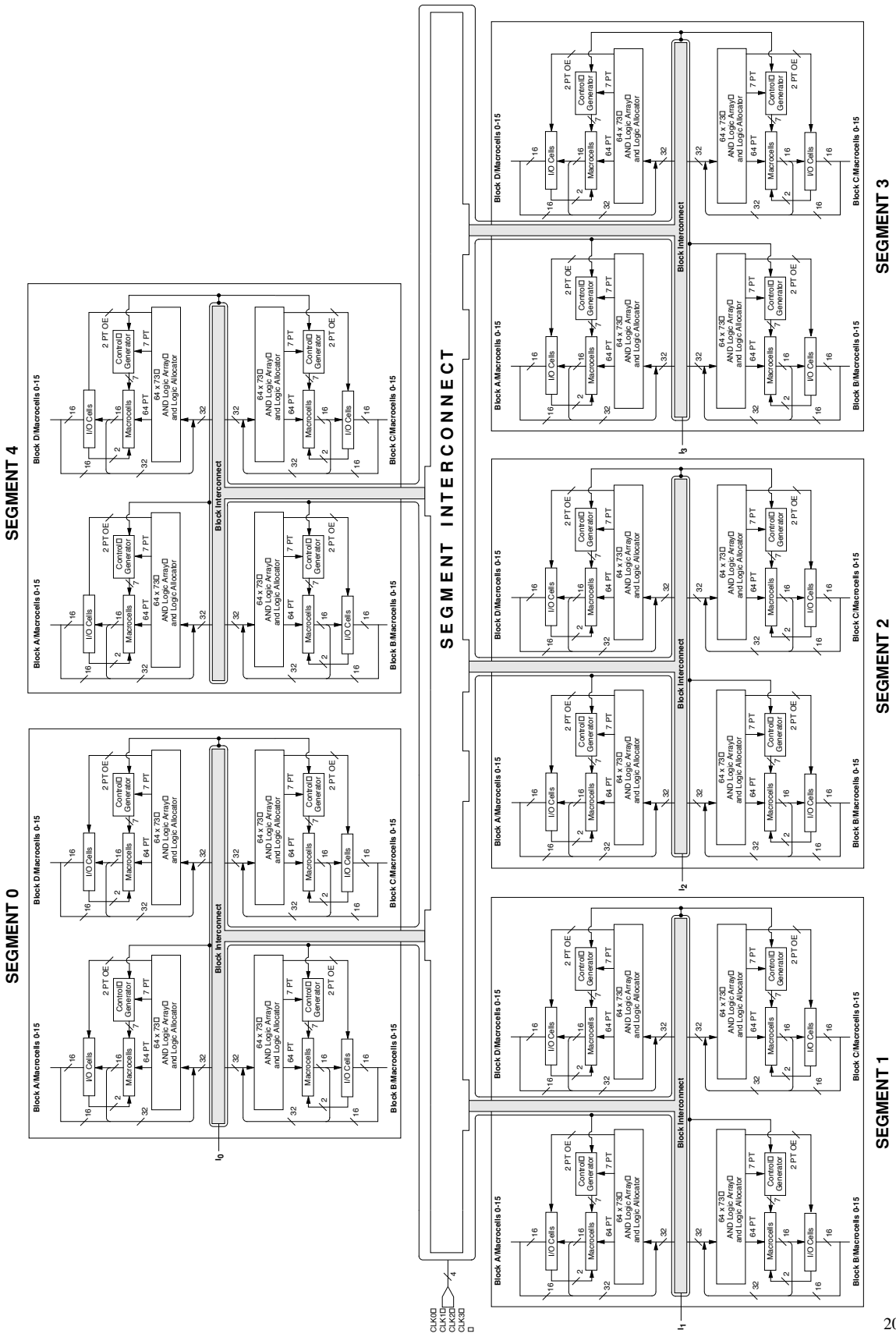
BLOCK DIAGRAM — M5(LV)-256/XXX



20446G-009

Select devices have been discontinued.
See Ordering Information section for product status.

BLOCK DIAGRAM — M5(LV)-320/XXX

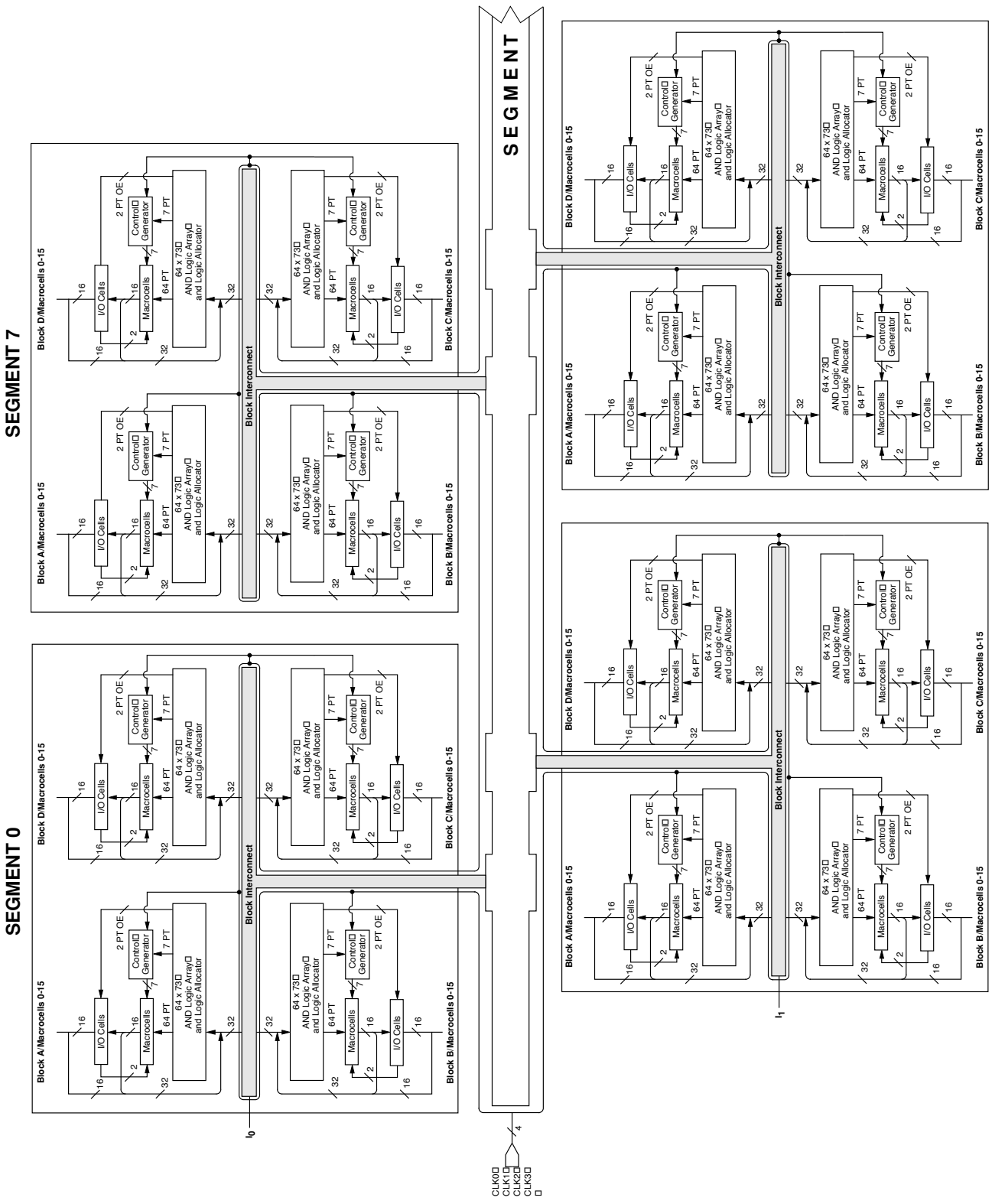


20446G-010

Select devices have been discontinued.
See Ordering Information section for product status.

BLOCK DIAGRAM — M5(LV)-512/XXX

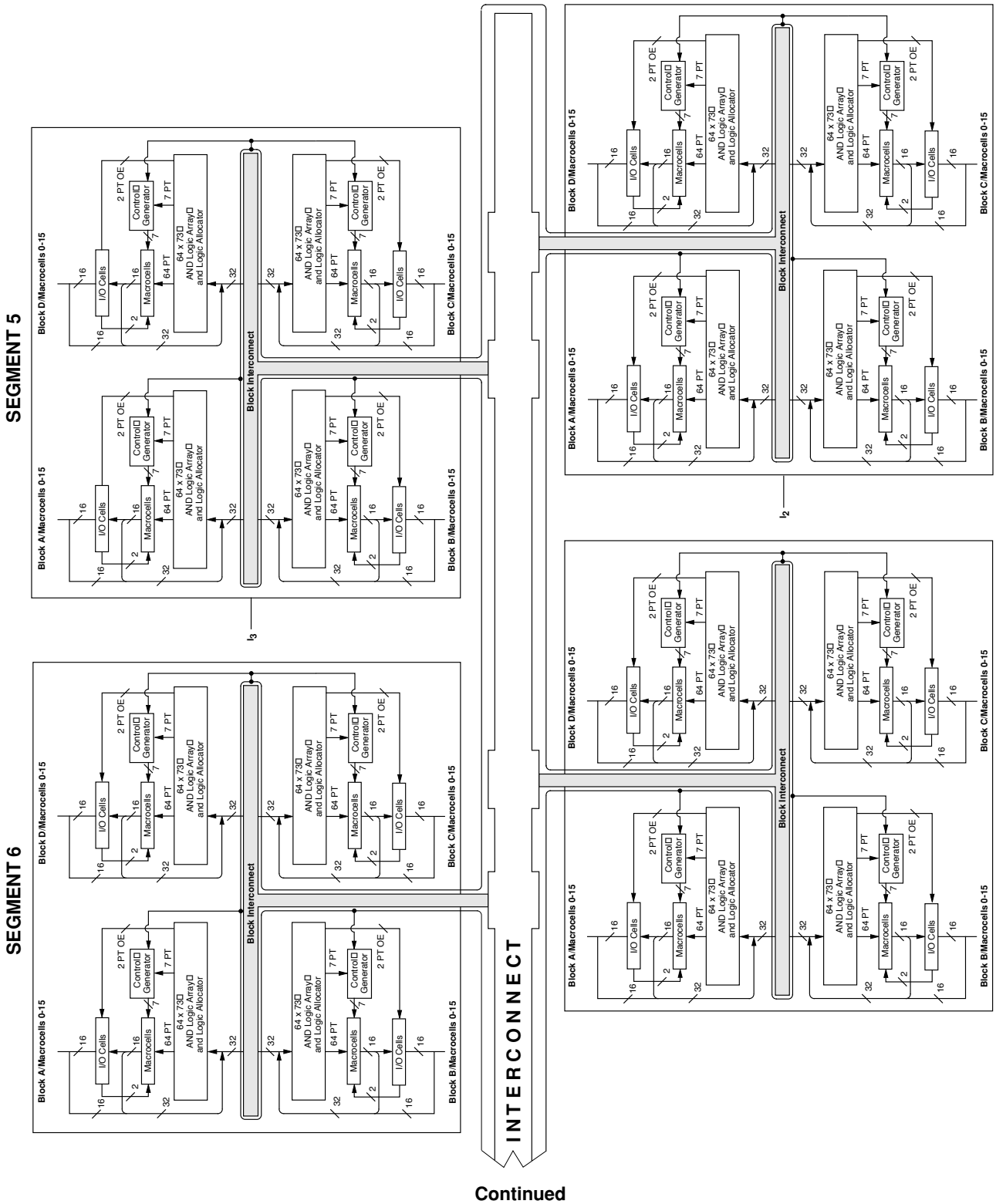
Continued



Select devices have been discontinued.
See Ordering Information section for product status.

20446G-012

BLOCK DIAGRAM — M5(LV)-512/XXX



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20446G-013

Select devices have been discontinued.
See Ordering Information section for product status.

M5(LV) TIMING PARAMETERS OVER OPERATING RANGES[1]

		-5		-6		-7		-10		-12		-15		-20		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
Combinatorial Delay:																
t_{PDi}	Internal combinatorial propagation delay		3.5		4.5		5.5		8.0		10.0		13.0		18.0	ns
t_{PD}	Combinatorial propagation delay		5.5		6.5		7.5		10.0		12.0		15.0		20.0	ns
Registered Delays:																
t_{SS}	Synchronous clock setup time	3.0		3.0		4.0		5.0		6.0		8.0		10.0		ns
t_{SA}	Asynchronous clock setup time	3.0		3.0		4.0		5.0		6.0		7.0		8.0		ns
t_{HS}	Synchronous clock hold time	0.0		0.0		0.0		0.0		0.0		0.0		0.0		ns
t_{HA}	Asynchronous clock hold time	3.0		3.0		4.0		5.0		6.0		7.0		8.0		ns
t_{COSi}	Synchronous clock to internal output		2.5		3.0		4.0		5.0		6.0		8.0		10.0	ns
t_{COS}	Synchronous clock to output		4.5		5.0		6.0		7.0		8.0		10.0		12.0	ns
t_{COAi}	Asynchronous clock to internal output		6.0		6.0		8.0		10.0		13.0		15.0		18.0	ns
t_{COA}	Asynchronous clock to output		8.0		8.0		10.0		12.0		15.0		17.0		20.0	ns
Latched Delays:																
t_{SAL}	Latch setup time	3.0		4.0		4.0		5.0		6.0		7.0		8.0		ns
t_{HAL}	Latch hold time	3.0		3.0		4.0		5.0		6.0		7.0		8.0		ns
t_{PDLi}	Transparent latch internal		6.0		7.0		7.0		8.0		9.0		10.0		10.0	ns
t_{PDL}	Propagation delay through transparent latch		8.0		9.0		9.0		10.0		11.0		12.0		12.0	ns
t_{GOAi}	Gate to internal output		7.0		8.0		8.0		9.0		10.0		11.0		12.0	ns
t_{GOA}	Gate to output		9.0		10.0		10.0		11.0		12.0		13.0		14.0	ns
Input Register Delays:																
t_{SIRS}	Input register setup time using a synchronous clock	2.0		2.0		2.0		3.0		3.0		3.0		3.0		ns
t_{SIRA}	Input register setup time using an asynchronous clock	0.0		0.0		0.0		0.0		0.0		0.0		0.0		ns
t_{HIRS}	Input register hold time using a synchronous clock	3.0		3.0		3.0		4.0		4.0		4.0		4.0		ns
t_{HIRA}	Input register hold time using an asynchronous clock	6.0		6.0		6.0		7.0		7.0		7.0		7.0		ns
Input Latch Delays:																
t_{SIL}	Input latch setup time	2.0		2.0		2.0		3.0		3.0		3.0		3.0		ns
t_{HIL}	Input latch hold time	6.0		6.0		6.0		7.0		7.0		7.0		7.0		ns
t_{PDILi}	Transparent input latch		5.0		5.0		5.5		6.0		6.0		6.0		6.0	ns
Output Delays:																
t_{BUF}	Output buffer delay		2.0		2.0		2.0		2.0		2.0		2.0		2.0	ns
t_{SLW}	Slow slew rate delay		2.5		2.5		2.5		2.5		2.5		2.5		2.5	ns
t_{EA}	Output enable time		7.5		7.5		9.5		10.0		12.0		15.0		20.0	ns
t_{ER}	Output disable time		7.5		7.5		9.5		10.0		12.0		15.0		20.0	ns

Select devices have been discontinued.
See Ordering Information section for product status.

M5(LV) TIMING PARAMETERS OVER OPERATING RANGES[1] (CONTINUED)

		-5		-6		-7		-10		-12		-15		-20		
		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Unit
Power Delays:																
t_{PL1}	Power level 1 delay (Note 2)		4.0 (5.0)		4.0		4.0 (5.0)		4.0 (5.0)		4.0 (5.0)		4.0 (5.0)		4.0 (5.0)	ns
t_{PL2}	Power level 2 delay (Note 2)		6.0 (9.0)		6.0		6.0 (9.0)		6.0 (9.0)		6.0 (9.0)		6.0 (9.0)		6.0 (9.0)	ns
t_{PL3}	Power level 3 delay (Note 2)		9.0 (17.5)		9.0		9.0 (17.5)		9.0 (17.5)		9.0 (17.5)		9.0 (17.5)		9.0 (17.5)	ns
Additional Cluster Delay:																
t_{PT}	Product term cluster delay		0.3		0.3		0.3		0.3		0.3		0.3		0.3	ns
Interconnect Delays:																
t_{BLK}	Block interconnect delay		1.5		1.5		1.5		2.0		2.0		2.0		2.0	ns
t_{SEG}	Segment interconnect delay		4.5		4.5		5.0		6.0		6.0		6.0		6.0	ns
Reset and Preset Delays:																
t_{SRi}	Asynchronous reset or preset to internal register output		6.0		8.0		8.0		10.0		12.0		14.0		16.0	ns
t_{SR}	Asynchronous reset or preset to register output		8.0		10.0		10.0		12.0		14.0		16.0		18.0	ns
t_{SRR}	Reset and set register recovery time	5.5		7.5		7.5		8.0		9.0		10.0		11.0		ns
t_{SRW}	Asynchronous reset or preset width	3.0		4.0		4.0		5.0		6.0		7.0		8.0		ns
Clock Enable Delays:																
t_{CES}	Clock enable setup time	4.0		5.0		5.0		6.0		7.0		7.0		8.0		ns
t_{CEH}	Clock enable hold time	3.0		4.0		4.0		5.0		6.0		6.0		7.0		ns
Width:																
t_{WLS}	Global clock width low (Note 3)	2.5		3.0		3.0		4.0		5.0		6.0		6.0		ns
t_{WHS}	Global clock width high (Note 3)	2.5		3.0		3.0		4.0		5.0		6.0		6.0		ns
t_{WLA}	Product term clock width low	3.0		4.0		4.0		5.0		6.0		7.0		8.0		ns
t_{WHA}	Product term clock width high	3.0		4.0		4.0		5.0		6.0		7.0		8.0		ns
t_{GWA}	Gate width low (for low transparent) or high (for high transparent)	3.0		4.0		4.0		5.0		6.0		7.0		8.0		ns
t_{WIR}	Input register clock width low or high	3.0		4.0		4.0		5.0		6.0		7.0		8.0		ns

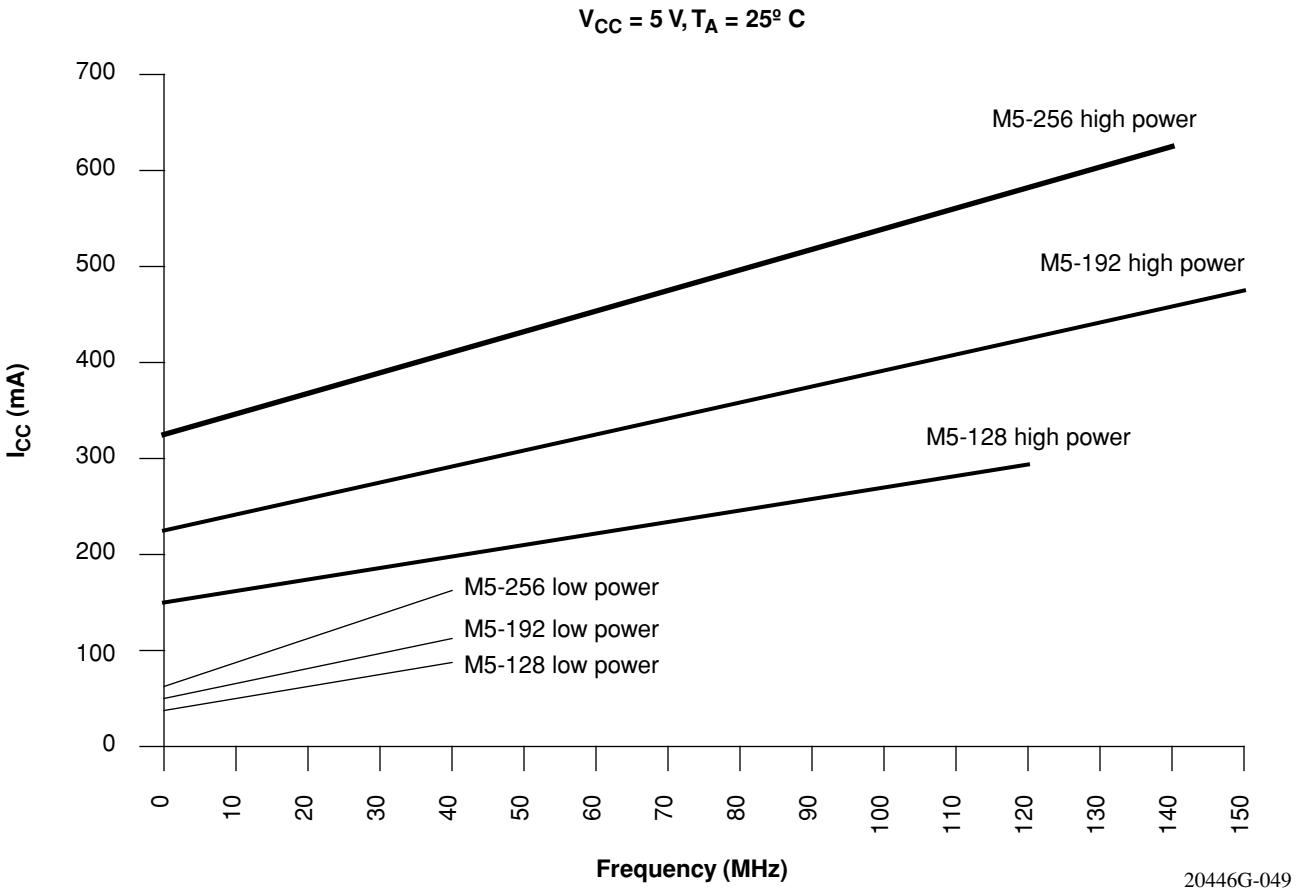
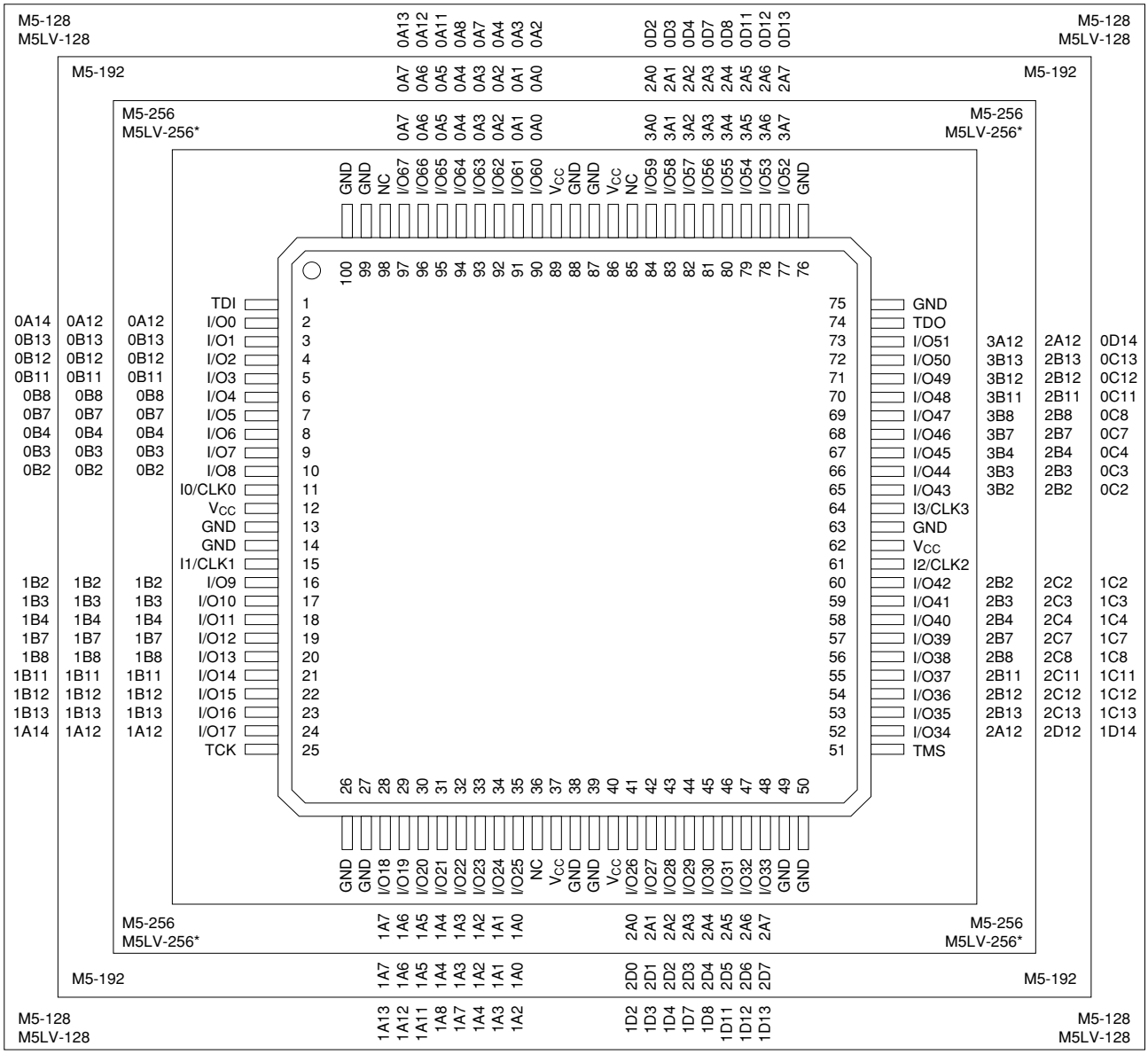


Figure 9. I_{CC} Curves at High/Low Power Modes

100-PIN TQFP CONNECTION DIAGRAM – 68 I/O

Top View

100-Pin TQFP (68 I/O)

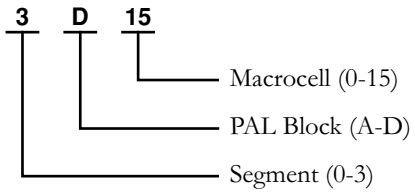


*Package obsolete, contact factory.

20446G-017

Pin Designations

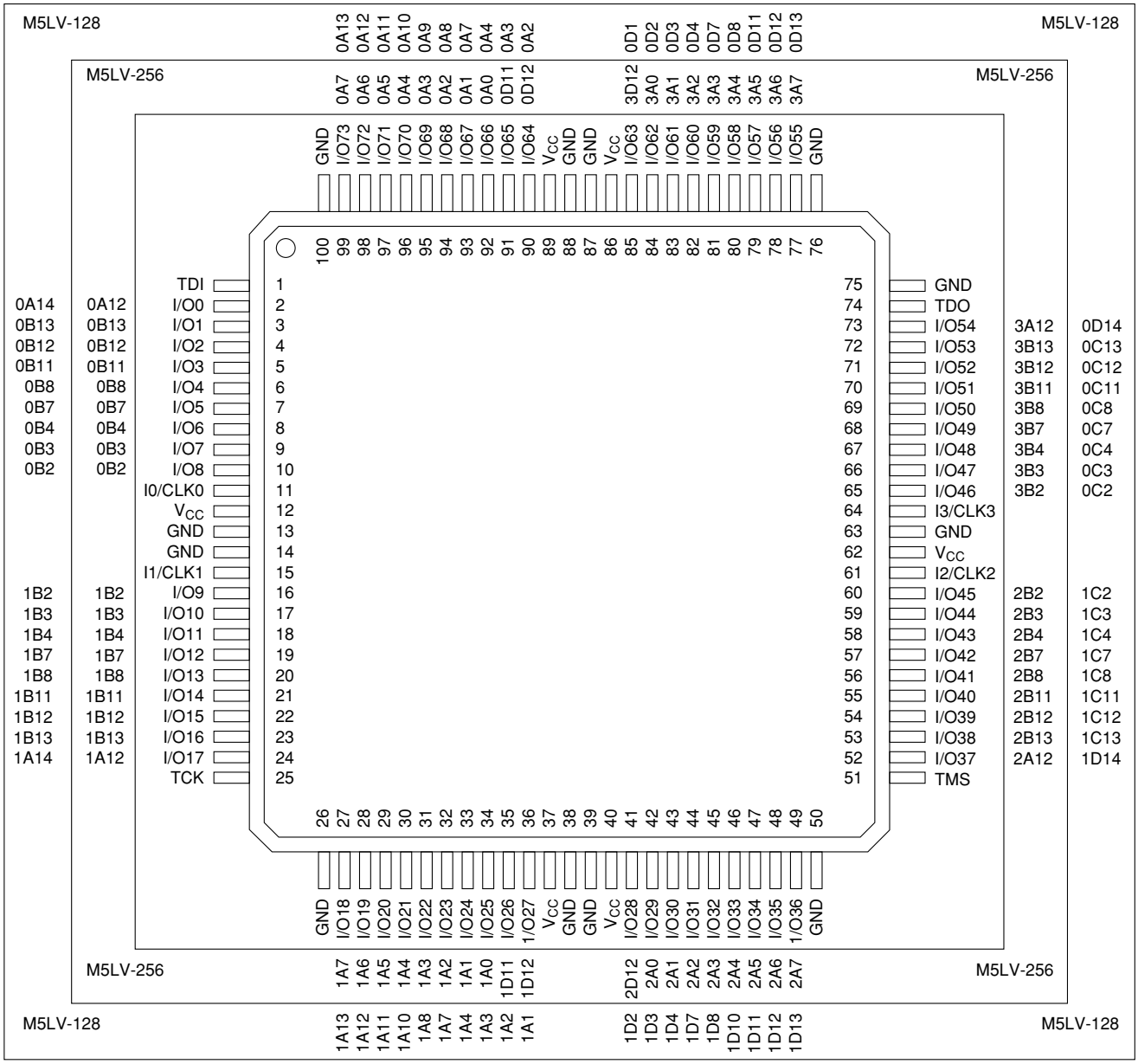
CLK	=	Clock	V_{CC}	=	Supply Voltage
GND	=	Ground	TDI	=	Test Data In
I	=	Input	TCK	=	Test Clock
I/O	=	Input/Output	TMS	=	Test Mode Select
NC	=	No Connect	TDO	=	Test Data Out



100-PIN TQFP CONNECTION DIAGRAM – 74 I/O

Top View

100-Pin TQFP (74 I/O)

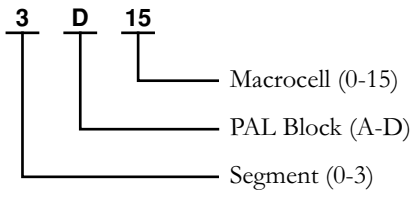


20446G-018

Select devices have been discontinued. See Ordering Information section for product status.

Pin Designations

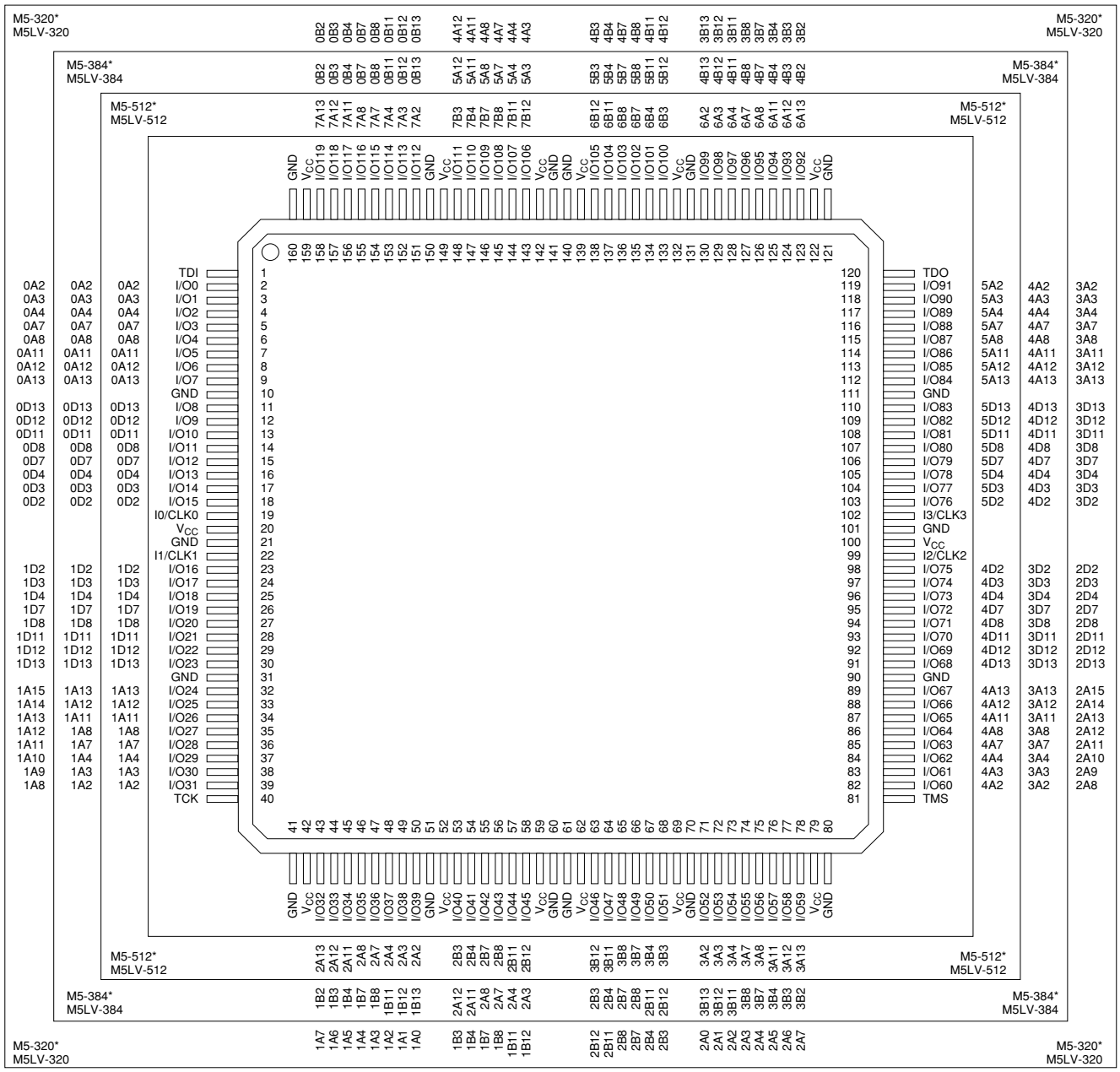
CLK	=	Clock	V_{CC}	=	Supply Voltage		
GND	=	Ground	TDI	=	Test Data In		
I	=	Input	TCK	=	Test Clock		
I/O	=	Input/Output	TMS	=	Test Mode Select		
NC	=	No Connect	TDO	=	Test Data Out		



160-PIN PQFP (WITH INTERNAL HEAT SPREADER) CONNECTION DIAGRAM

Top View

160-Pin PQFP (320, 384, 512 Macrocells)



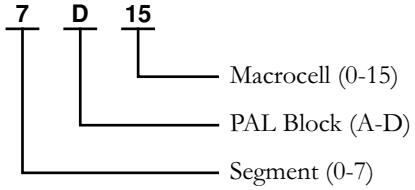
*Package obsolete, contact factory.

20446G-022

Select devices have been discontinued. See Ordering Information section for product status.

Pin Designations

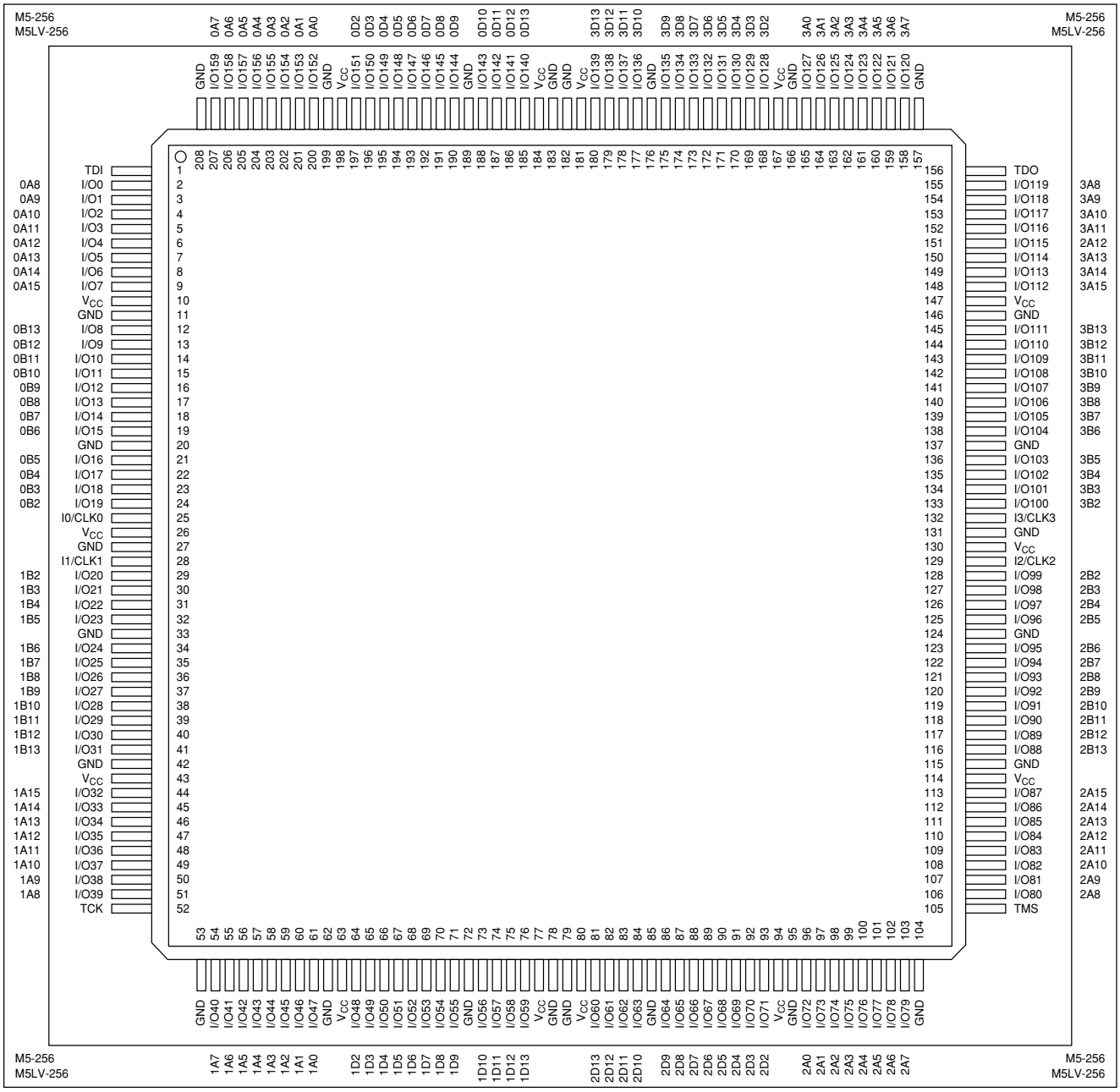
CLK	=	Clock	V_{CC}	=	Supply Voltage
GND	=	Ground	TDI	=	Test Data In
I	=	Input	TCK	=	Test Clock
I/O	=	Input/Output	TMS	=	Test Mode Select
NC	=	No Connect	TDO	=	Test Data Out



208-PIN PQFP CONNECTION DIAGRAM

Top View

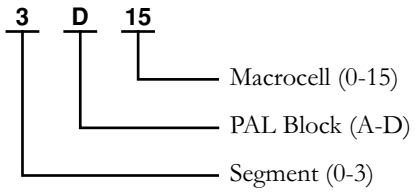
208-Pin PQFP (256 Macrocells)



20446G-023

Pin Designations

CLK	=	Clock	V_{CC}	=	Supply Voltage
GND	=	Ground	TDI	=	Test Data In
I	=	Input	TCK	=	Test Clock
I/O	=	Input/Output	TMS	=	Test Mode Select
NC	=	No Connect	TDO	=	Test Data Out

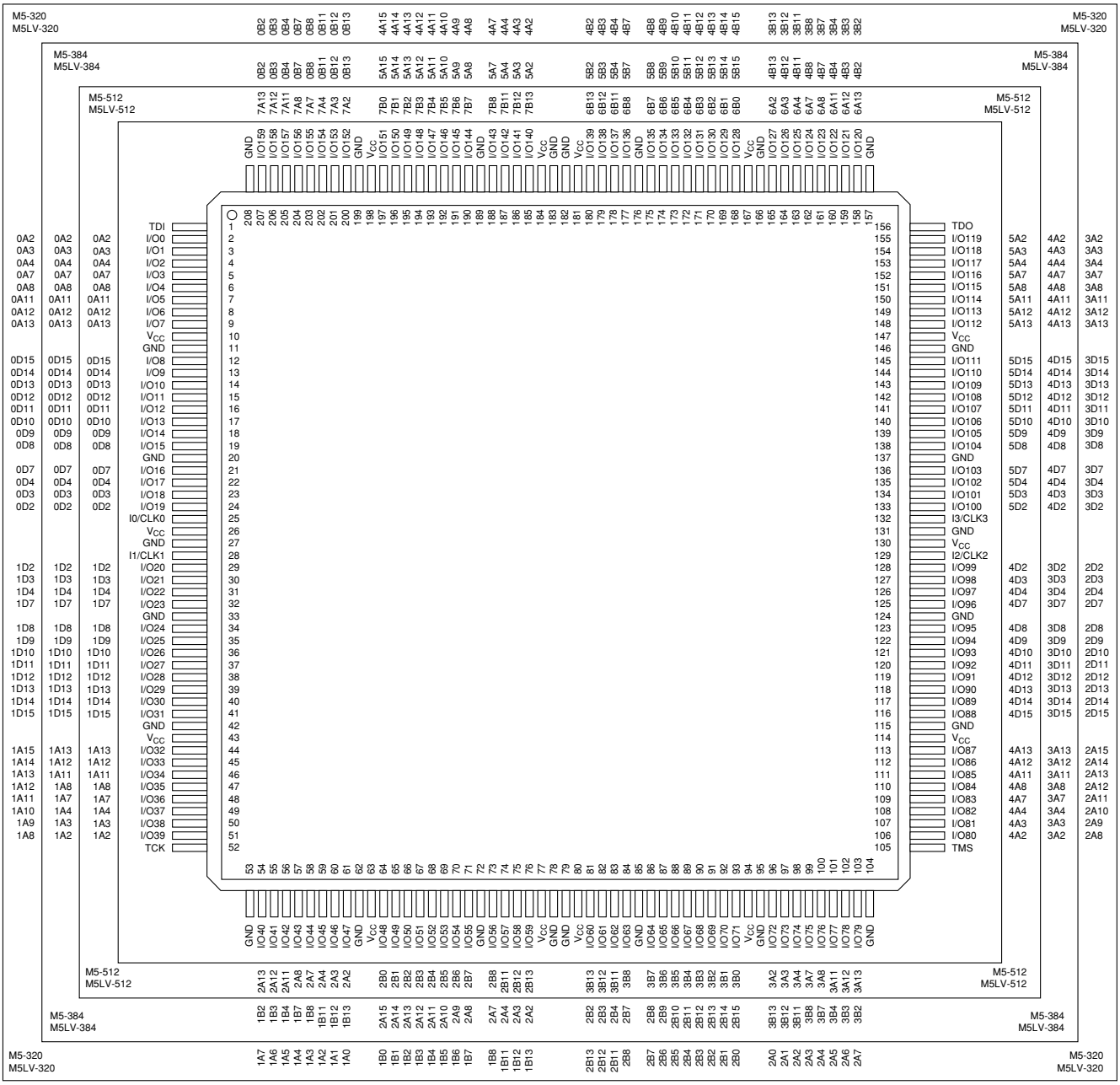


Select devices have been discontinued. See Ordering Information section for product status.

208-PIN PQFP (WITH INTERNAL HEAT SPREADER) CONNECTION DIAGRAM

Top View

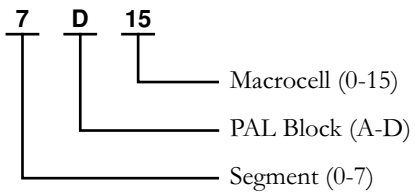
208-Pin PQFP (320, 384, 512 Macrocells)



20446G-024

Pin Designations

CLK	=	Clock	V_{CC}	=	Supply Voltage
GND	=	Ground	TDI	=	Test Data In
I	=	Input	TCK	=	Test Clock
I/O	=	Input/Output	TMS	=	Test Mode Select
NC	=	No Connect	TDO	=	Test Data Out



Select devices have been discontinued. See Ordering Information section for product status.

256-BALL BGA CONNECTION DIAGRAM — M5-320

Bottom View (I/O Pin-outs)

256-Ball BGA

	A	B	C	D	E	F	G	H	J	K	L	M	N	P	R	T	U	V	W	Y	
1	GND	GND	I/O181	I/O182	I/O183	GND	I/O184	GND	I/O185	I/O186	GND	I/O187	GND	I/O188	GND	I/O189	I/O190	I/O191	GND	GND	1
2	GND	I/O164	I/O165	I/O166	I/O167	I/O168	I/O169	I/O170	I/O171	I3/CLK3	I2/CLK2	I/O172	I/O173	I/O174	I/O175	I/O176	I/O177	I/O178	I/O179	I/O180	2
3	GND	I/O148	V_{CC}	I/O149	I/O150	I/O151	I/O152	I/O153	I/O154	I/O155	I/O156	I/O157	I/O158	I/O159	I/O160	I/O161	I/O162	V_{CC}	I/O163	GND	3
4	I/O134	I/O135	I/O136	V_{CC}	TDO	I/O137	V_{CC}	I/O138	I/O139	I/O140	I/O141	I/O142	I/O143	V_{CC}	I/O144	TMS	V_{CC}	I/O145	I/O146	I/O147	4
5	I/O128	I/O129	I/O130	V_{CC}													V_{CC}	I/O131	I/O132	I/O133	5
6	GND	I/O122	I/O123	I/O124													I/O125	I/O126	I/O127	GND	6
7	I/O116	I/O117	I/O118	V_{CC}													V_{CC}	I/O119	I/O120	I/O121	7
8	I/O108	I/O109	I/O110	I/O111													I/O112	I/O113	I/O114	I/O115	8
9	GND	I/O102	I/O103	I/O104													I/O105	I/O106	I/O107	GND	9
10	GND	I/O96	I/O97	I/O98													I/O99	I/O100	I/O101	GND	10
11	GND	I/O90	I/O91	I/O92													I/O93	I/O94	I/O95	GND	11
12	GND	I/O84	I/O85	I/O86													I/O87	I/O88	I/O89	GND	12
13	I/O76	I/O77	I/O78	I/O79													I/O80	I/O81	I/O82	I/O83	13
14	I/O70	I/O71	I/O72	V_{CC}													V_{CC}	I/O73	I/O74	I/O75	14
15	GND	I/O64	I/O65	I/O66													I/O67	I/O68	I/O69	GND	15
16	I/O58	I/O59	I/O60	V_{CC}													V_{CC}	I/O61	I/O62	I/O63	16
17	I/O44	I/O45	I/O46	V_{CC}	TDI	I/O47	V_{CC}	I/O48	I/O49	I/O50	I/O51	I/O52	I/O53	V_{CC}	I/O54	TCK	V_{CC}	I/O55	I/O56	I/O57	17
18	GND	I/O28	V_{CC}	I/O29	I/O30	I/O31	I/O32	I/O33	I/O34	I/O35	I/O36	I/O37	I/O38	I/O39	I/O40	I/O41	I/O42	V_{CC}	I/O43	GND	18
19	I/O11	I/O12	I/O13	I/O14	I/O15	I/O16	I/O17	I/O18	I/O19	IO/CLK0	I1/CLK1	I/O20	I/O21	I/O22	I/O23	I/O24	I/O25	I/O26	I/O27	GND	19
20	GND	GND	I/O0	I/O1	I/O2	GND	I/O3	GND	I/O4	GND	I/O5	I/O6	GND	I/O7	GND	I/O8	I/O9	I/O10	GND	GND	20
	A	B	C	D	E	F	G	H	J	K	L	M	N	P	R	T	U	V	W	Y	

Pin Designations

CLK	=	Clock
GND	=	Ground
I	=	Input
I/O	=	Input/Output
NC	=	No Connect
V_{CC}	=	Supply Voltage
TDI	=	Test Data In
TCK	=	Test Clock
TMS	=	Test Mode Select
TDO	=	Test Data Out

20446G-026

Select devices have been discontinued.
See Ordering Information section for product status.

352-BALL BGA CONNECTION DIAGRAM — M5-512, M5LV-512

Bottom View (I/O Pin-outs)

352-Ball BGA

	A	B	C	D	E	F	G	H	J	K	L	M	N	P	R	T	U	V	W	Y	AA	AB	AC	AD	AE	AF	
1	NC	NC	NC	GND	NC	I/O245	GND	I/O246	I/O247	GND	I/O248	I/O249	I3/CLK3	GND	I/O250	I/O251	I/O252	GND	I/O253	I/O254	GND	NC	I/O255	GND	NC	NC	1
2	NC	NC	NC	I/O224	I/O225	I/O226	I/O227	I/O228	I/O229	I/O230	I/O231	I/O232	I/O233	I2CLK2	I/O235	I/O236	I/O237	I/O238	I/O239	I/O240	I/O241	I/O242	I/O243	I/O244	GND	GND	2
3	GND	GND	NC	I/O205	I/O206	I/O207	I/O208	I/O209	I/O210	I/O211	I/O212	I/O213	I/O214	I2CLK2	I/O215	I/O216	I/O217	I/O218	I/O219	I/O220	I/O221	I/O222	I/O223	TMS	NC	NC	3
4	NC	I/O188	NC	TDO	I/O189	I/O190	I/O191	V_{CC}	I/O192	V_{CC}	I/O193	I/O194	I/O195	V_{CC}	I/O196	I/O197	I/O198	V_{CC}	I/O199	V_{CC}	I/O200	I/O201	V_{CC}	I/O202	I/O203	I/O204	4
5	GND	I/O183	I/O184	V_{CC}																			I/O185	I/O186	I/O187	GND	5
6	NC	I/O176	I/O177	I/O178																			I/O179	I/O180	I/O181	I/O182	6
7	GND	I/O169	I/O170	I/O171																			I/O172	I/O173	I/O174	I/O175	7
8	I/O162	I/O163	I/O164	I/O165																			I/O166	I/O167	I/O168	NC	8
9	I/O156	I/O157	I/O158	I/O159																			V_{CC}	I/O160	I/O161	GND	9
10	GND	I/O150	I/O151	V_{CC}																			I/O152	I/O153	I/O154	I/O155	10
11	I/O142	I/O143	I/O144	I/O145																			I/O146	I/O147	I/O148	I/O149	11
12	I/O134	I/O135	I/O136	I/O137																			I/O138	I/O139	I/O140	I/O141	12
13	I/O128	I/O129	I/O130	I/O131																			V_{CC}	I/O132	I/O133	GND	13
14	GND	I/O122	I/O123	V_{CC}																			I/O124	I/O125	I/O126	I/O127	14
15	I/O114	I/O115	I/O116	I/O117																			I/O118	I/O119	I/O120	I/O121	15
16	NC	I/O107	I/O108	I/O109																			I/O110	I/O111	I/O112	I/O113	16
17	I/O101	I/O102	I/O103	I/O104																			V_{CC}	I/O105	I/O106	GND	17
18	GND	I/O95	I/O96	V_{CC}																			I/O97	I/O98	I/O99	I/O100	18
19	I/O87	I/O88	I/O89	I/O90																			I/O91	I/O92	I/O93	I/O94	19
20	I/O80	I/O81	I/O82	I/O83																			I/O84	I/O85	I/O86	GND	20
21	I/O73	I/O74	I/O75	I/O76																			I/O77	I/O78	I/O79	NC	21
22	GND	I/O68	I/O69	I/O70																			V_{CC}	I/O71	I/O72	GND	22
23	I/O51	I/O52	I/O53	V_{CC}	I/O54	I/O55	V_{CC}	I/O56	V_{CC}	I/O57	I/O58	I/O59	V_{CC}	I/O60	I/O61	I/O62	V_{CC}	I/O63	V_{CC}	I/O64	I/O65	I/O66	TCK	NC	I/O67	NC	23
24	NC	NC	TDI	I/O32	I/O33	I/O34	I/O35	I/O36	I/O37	I/O38	I/O39	I/O40	I0/CLK0	I/O41	I/O42	I/O43	I/O44	I/O45	I/O46	I/O47	I/O48	I/O49	I/O50	NC	GND	GND	24
25	GND	GND	I/O11	I/O12	I/O13	I/O14	I/O15	I/O16	I/O17	I/O18	I/O19	I/O20	I/O21	I/O22	I/O23	I/O24	I/O25	I/O26	I/O27	I/O28	I/O29	I/O30	I/O31	NC	NC	NC	25
26	NC	NC	GND	I/O0	NC	GND	I/O1	I/O2	GND	I/O3	I/O4	I/O5	GND	I1/CLK1	I/O6	I/O7	GND	I/O8	I/O9	GND	I/O10	NC	GND	NC	NC	NC	26
	A	B	C	D	E	F	G	H	J	K	L	M	N	P	R	T	U	V	W	Y	AA	AB	AC	AD	AE	AF	

20446G-030

Pin Designations

CLK	=	Clock
GND	=	Ground
I	=	Input
I/O	=	Input/Output
NC	=	No Connect
V_{CC}	=	Supply Voltage
TDI	=	Test Data In
TCK	=	Test Clock
TMS	=	Test Mode Select
TDO	=	Test Data Out

Select devices have been discontinued.
See Ordering Information section for product status.

352-BALL BGA CONNECTION DIAGRAM — M5-512, M5LV-512

Bottom View (Macrocell Association)

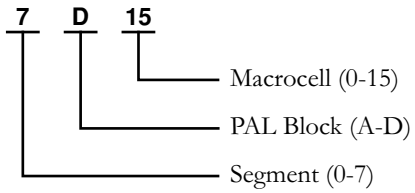
352-Ball BGA

	A	B	C	D	E	F	G	H	J	K	L	M	N	P	R	T	U	V	W	Y	AA	AB	AC	AD	AE	AF	
1	NC	NC	NC	GND	NC	5A12	GND	5D15	5D11	GND	5D6	5D3	I3/CLK3	GND	4D1	4D5	4D9	GND	4D15	4A13	GND	NC	4A6	GND	NC	NC	1
2	NC	NC	NC	5A2	5A5	5A9	5A14	5A15	5D13	5D10	5D8	5D4	5D0	4D0	4D2	4D6	4D10	4D13	4A15	4A12	4A9	4A8	4A3	4A1	GND	GND	2
3	GND	GND	NC	5A1	5A4	5A7	5A8	5A10	5A13	5D14	5D9	5D5	5D1	I2/CLK2	4D4	4D7	4D11	4D14	4A14	4A10	4A7	4A5	4A2	TMS	NC	NC	3
4	NC	6A14	NC	TDO	5A0	5A3	5A6	V_{CC}	5A11	V_{CC}	5D12	5D7	5D2	V_{CC}	4D3	4D8	4D12	V_{CC}	4A11	V_{CC}	4A4	4A0	V_{CC}	3A15	3A13	3A12	4
5	GND	6A12	6A13	V_{CC}																			3A14	3A11	3A9	GND	5
6	NC	6A9	6A10	6A15																			3A10	3A8	3A7	3A5	6
7	GND	6A6	6A8	6A11																			3A6	3A4	3A3	3A0	7
8	6A1	6A4	6A5	6A7																			3A2	3A1	3B0	NC	8
9	6B1	6A0	6A2	6A3																			V_{CC}	3B1	3B2	GND	9
10	GND	6B2	6B0	V_{CC}																			3B3	3B4	3B5	3B6	10
11	6B6	6B5	6B4	6B3																			3B7	3B8	3B9	3B10	11
12	6B10	6B9	6B8	6B7																			3B11	3B12	3B13	3B14	12
13	6B14	6B13	6B12	6B11																			V_{CC}	2B15	3B15	GND	13
14	GND	7B15	6B15	V_{CC}																			2B11	2B12	2B13	2B14	14
15	7B14	7B13	7B12	7B11																			2B7	2B8	2B9	2B10	15
16	NC	7B10	7B9	7B8																			2B3	2B4	2B5	2B6	16
17	7B7	7B6	7B5	7B4																			V_{CC}	2B0	2B2	GND	17
18	GND	7B3	7B2	V_{CC}																			2A3	2A2	2A0	2B1	18
19	7B1	7B0	7A1	7A4																			2A7	2A5	2A4	2A1	19
20	7A0	7A2	7A3	7A8																			2A11	2A8	2A6	GND	20
21	7A5	7A6	7A7	7A12																			2A15	2A10	2A9	NC	21
22	GND	7A9	7A11	7A15																			V_{CC}	2A13	2A12	GND	22
23	7A10	7A13	7A14	V_{CC}	0A0	0A4	V_{CC}	0A11	V_{CC}	0D12	0D8	0D3	V_{CC}	1D2	1D7	1D12	V_{CC}	1A11	V_{CC}	1A6	1A3	1A0	TCK	NC	2A14	NC	23
24	NC	NC	TDI	0A2	0A5	0A7	0A10	0A14	0D14	0D11	0D7	0D4	I0/CLK0	1D1	1D5	1D9	1D14	1A13	1A10	1A8	1A7	1A4	1A1	NC	GND	GND	24
25	GND	GND	0A1	0A3	0A8	0A9	0A12	0A15	0D13	0D10	0D6	0D2	0D0	1D0	1D4	1D8	1D10	1D13	1A15	1A14	1A9	1A5	1A2	NC	NC	NC	25
26	NC	NC	GND	0A6	NC	GND	0A13	0D15	GND	0D9	0D5	0D1	GND	I1/CLK1	1D3	1D6	GND	1D11	1D15	GND	1A12	NC	GND	NC	NC	NC	26
	A	B	C	D	E	F	G	H	J	K	L	M	N	P	R	T	U	V	W	Y	AA	AB	AC	AD	AE	AF	

20446G-031

Pin Designations

CLK	=	Clock
GND	=	Ground
I	=	Input
I/O	=	Input/Output
NC	=	No Connect
V_{CC}	=	Supply Voltage
TDI	=	Test Data In
TCK	=	Test Clock
TMS	=	Test Mode Select
TDO	=	Test Data Out



Select devices have been discontinued.
See Ordering Information section for product status.

5V M5 ORDERING INFORMATION[1,2]

Lattice standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of the elements below.

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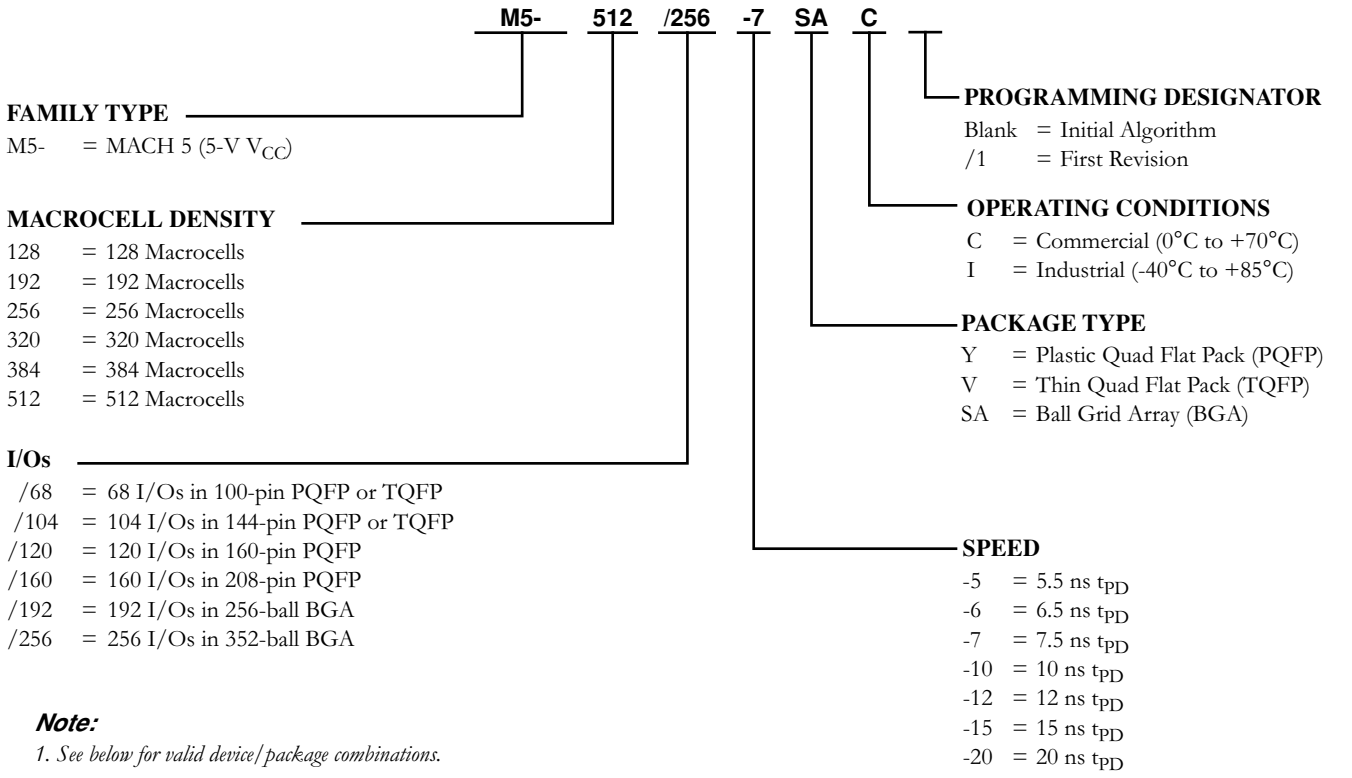

Note:

1. See below for valid device/package combinations.

2. M5-128/1, M5-192/1 and M5-256/1 recommended for new designs.

Valid Combinations		
M5-128/68	Commercial: -5, -7, -10, -12, -15 Industrial: -7, -10, -12, -15, -20	YC, VC, YI, VI
M5-128/104		YC[1], YI[1]
M5-128/120		YC, YI
M5-192/68		VC, VI
M5-192/120		YC, YI
M5-256/68		VC, VI
M5-256/120		YC, YI
M5-256/160		YC, YI

Device Marking

Actual device marking differs from the ordering part number (OPN). All MACH devices are dual-marked with both Commercial and Industrial grades. The Industrial grade is slower, i.e., M5-512/256-7AC-10AI.

1. M5-128/104-xxYC/1 and M5-128/104-xxYI/1 have been discontinued per PCN #06-07. Contact Rochester Electronics for available inventory.

Valid Combinations		
M5-320/160	Commercial: -6, -7, -10, -12, -15 Industrial: -7, -10, -12, -15, -20	YC, YI
M5-320/192		SAC, SAI
M5-384/160		YC, YI
M5-512/160		YC, YI
M5-512/256		SAC, SAI

Valid Combinations

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local Lattice sales office to confirm availability of specific valid combinations and to check on newly released combinations.

Select devices have been discontinued. See Ordering Information section for product status.